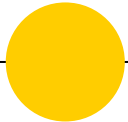




# WPI

# Particle Motion During Magnetron Sputter Deposition

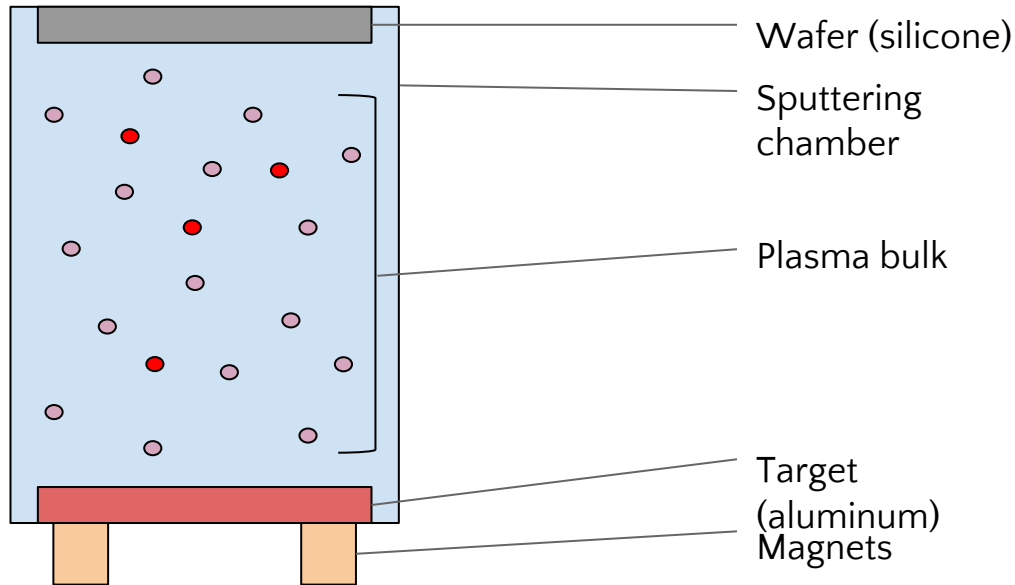


Benjamin Newmark  
Kylie Sullivan

A Major Qualifying Project Submitted to the Faculty of WPI, completed in  
partial fulfillment of the requirements for the Degree of Bachelor of Science.



# Magnetron Sputtering Deposition



## What is it?

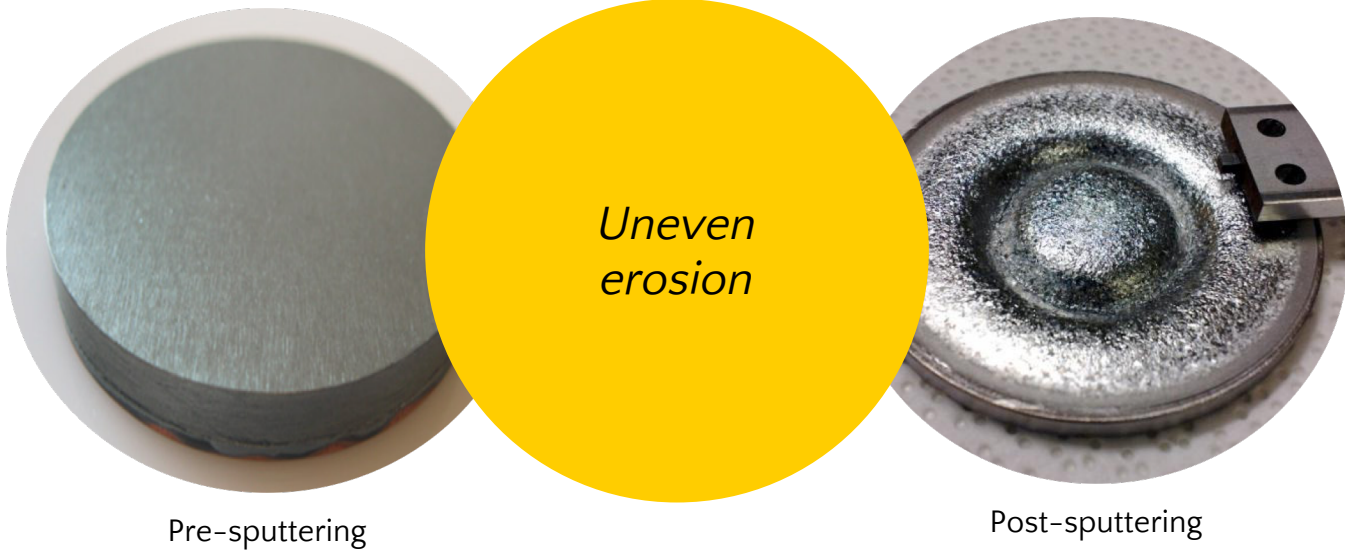
- Plasma-assisted thin film deposition technique
- Target erosion through particle bombardment

## Why is it used?

- Used for creating semiconductor materials (integrating computing chips, electron microscope slides)

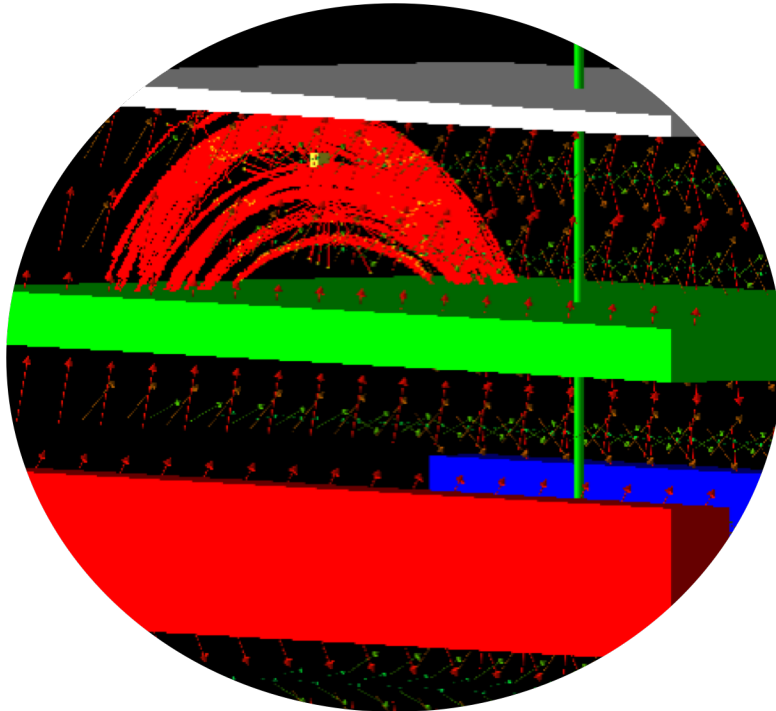


## Target erosion





# Particle Motion Simulation



**What could we control?**

- Electron energy
- Magnetic field strength
- Electric field strength

**What was native to Geant4?**

- Electron motion paths



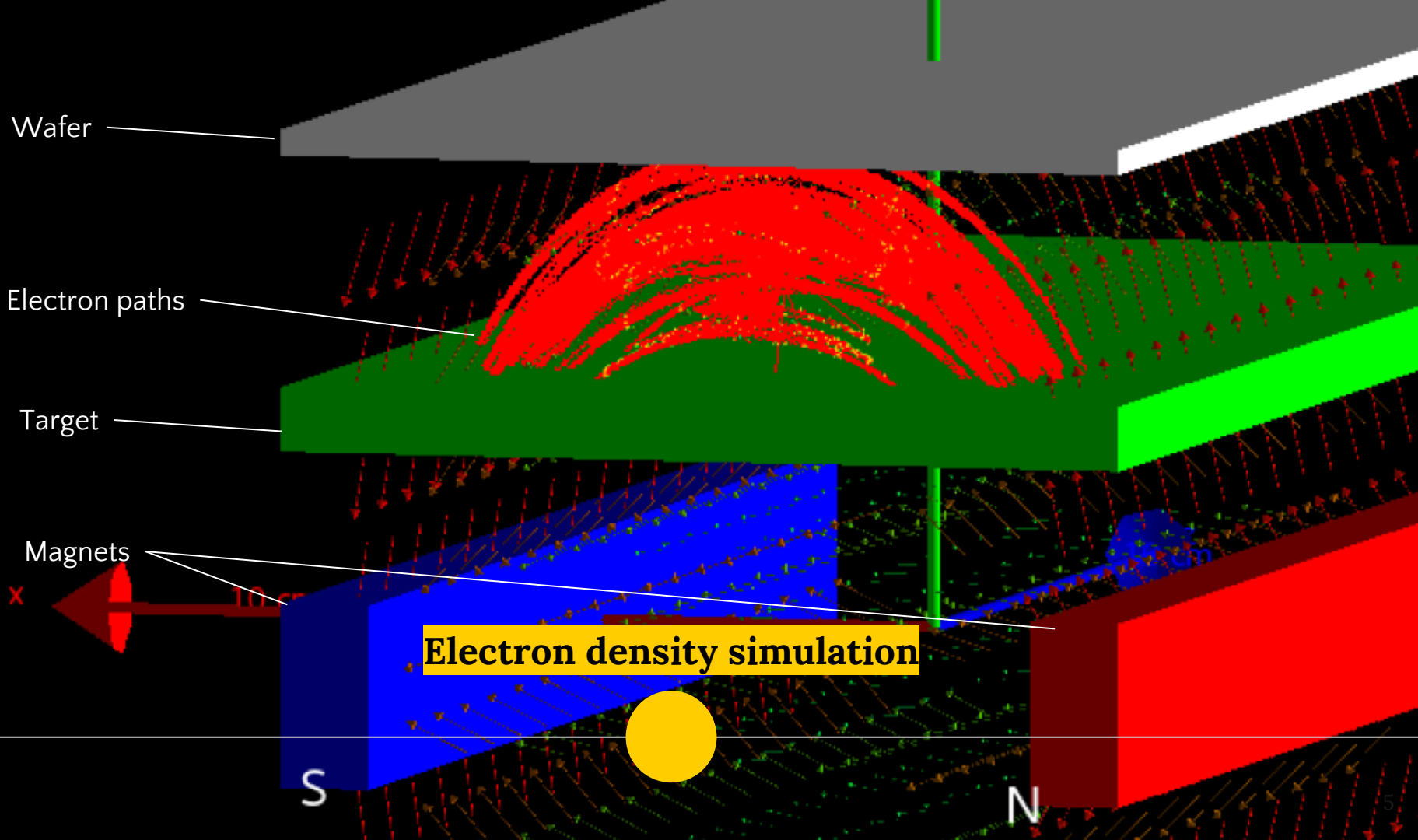
Wafer

Electron paths

Target

Magnets

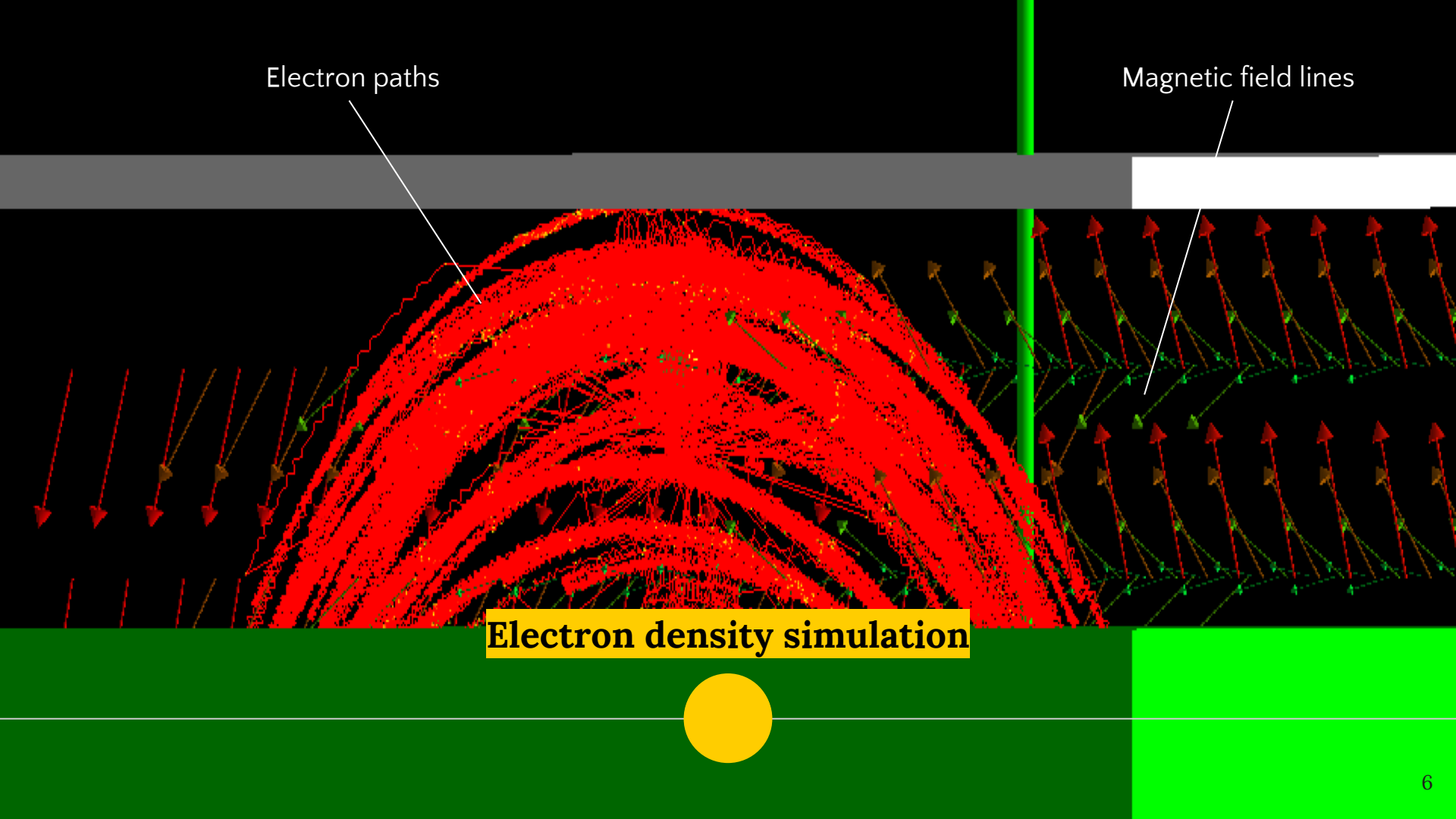
**Electron density simulation**



Electron paths

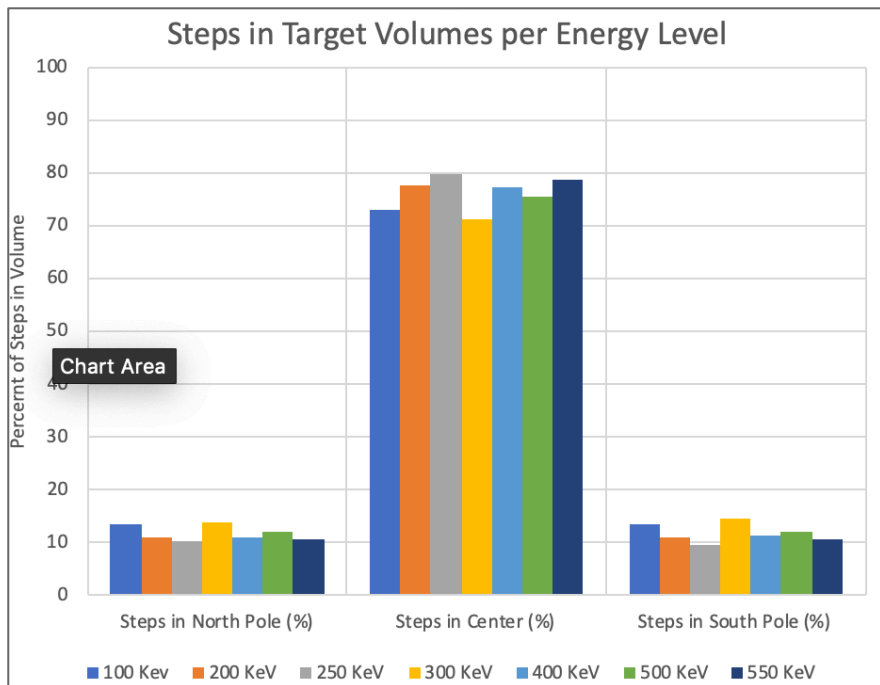
Magnetic field lines

**Electron density simulation**





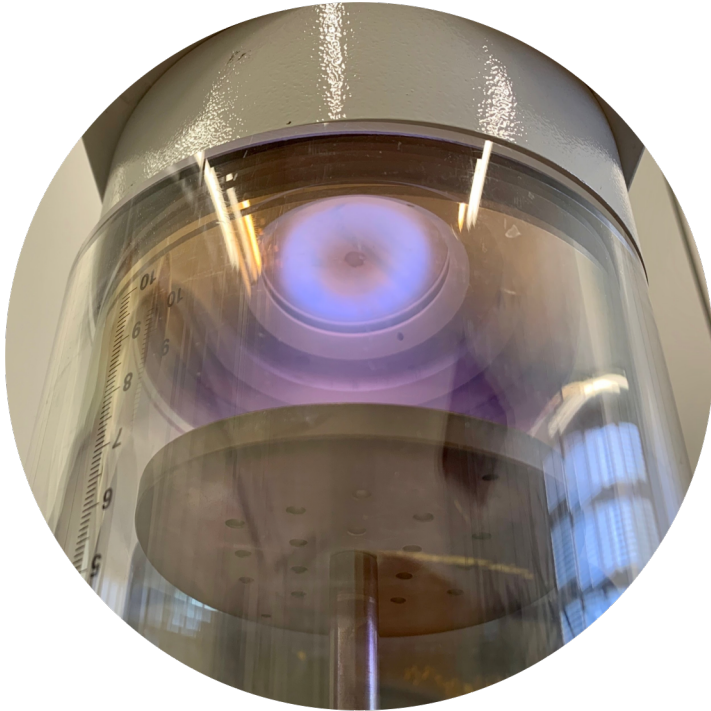
## Simulation Results



Electron Energy (KeV)	Steps in North Pole (%)	Steps in Center (%)	Steps in South Pole (%)
100	13.49	72.96	13.55
200	11.21	77.66	11.13
250	10.35	79.91	9.74
300	13.87	71.38	14.75
400	11.08	77.48	11.44
500	12.14	75.70	12.16
550	10.57	78.90	10.53



# Sputtering Experiments



## What was done?

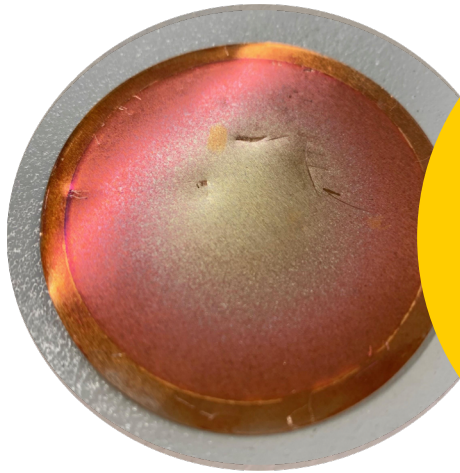
- Different targets were sputtered using a small sputtering chamber

## Why were experiments conducted?

- Track how erosion patterns change based on target material
- Predict how long a target could be used before becoming over-sputtered and worn out

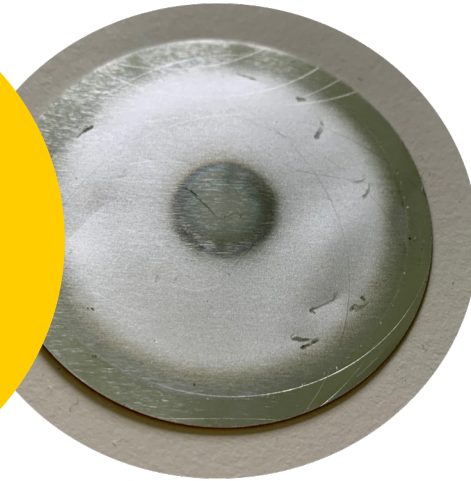


## Sputtering Results



Copper target  
after sputtering

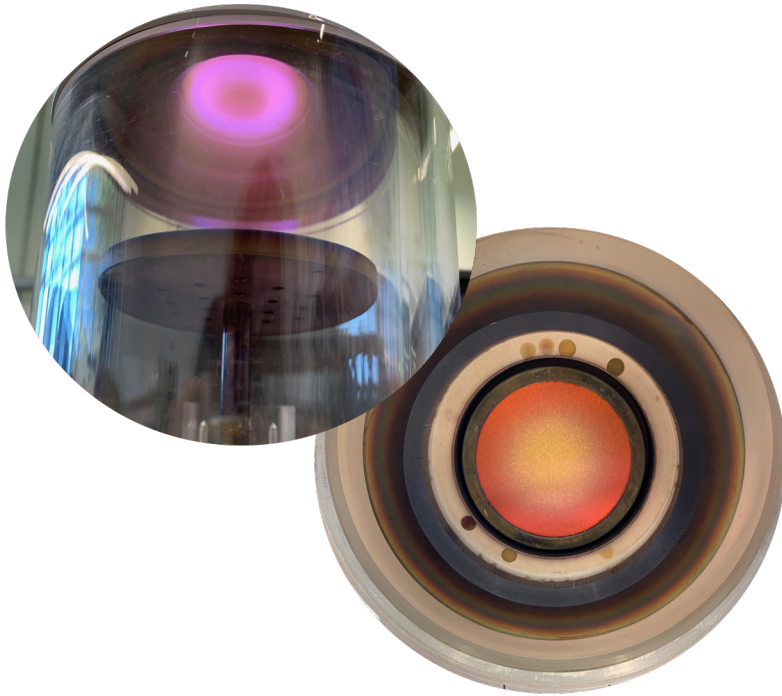
*Erosion  
patterns differ  
based on  
material*



Aluminum target  
after sputtering



## Conclusions



Erosion patterns change based on:

- ☐ Particle energy
- ☒ Magnet strength/placement
- ☒ Target material

Future work:

- Use simulation to change magnet placement and strength
- Simulate ion-electron interactions
- Institute electron tracking in labs at NTB



## Acknowledgements

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